

Supplementary Material

Polyaniline nanofibers-graphene oxide nanoplatelets composite thin film electrodes for electrochemical capacitors

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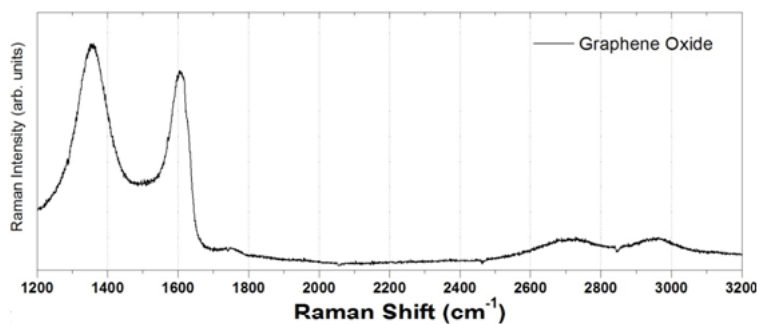


Fig. SI 1 X-ray diffraction pattern of GO.

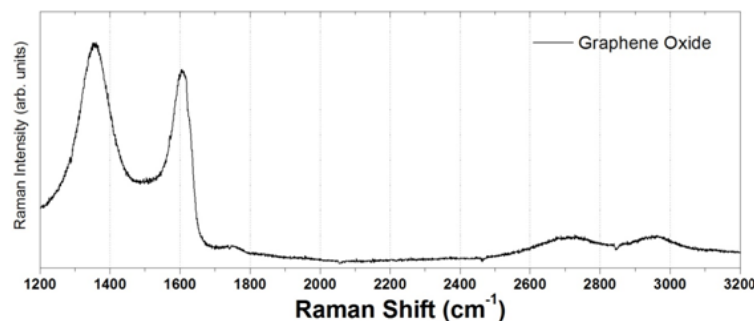


Fig. SI 2 Raman spectrum of GO. Excitation with 514 nm laser beam.

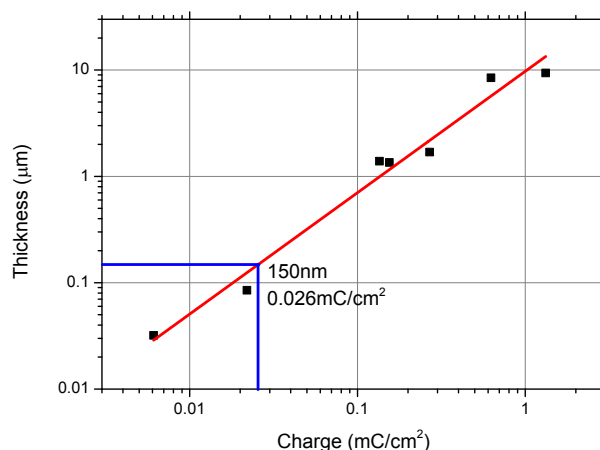


Fig. SI 3 Thickness vs. charges (sample PG-C).

C 1s spectrum of PANI-GO

Notably, a peak centered at about 285.7 eV corresponds to the C-N bond of PANI as described in previous work [Ref. SI 1-3]. The peak located at 287.2 eV, correspond to C=O bond of the amide group [Ref. SI 2]. This is probably due to the hydrogen bonds between the PANI and GO [Ref. SI 4]. The peaks at 284.8 eV and 286.3 eV represents the C-C/C-H and C=O of GO, respectively [Ref. SI 5].

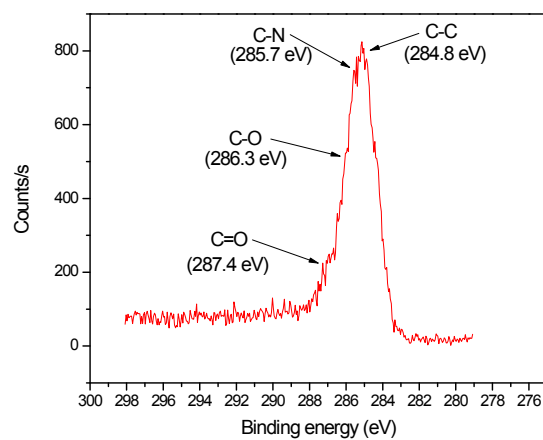


Fig. SI 4 High resolution C 1s spectrum of PANI-GO (PG-C).

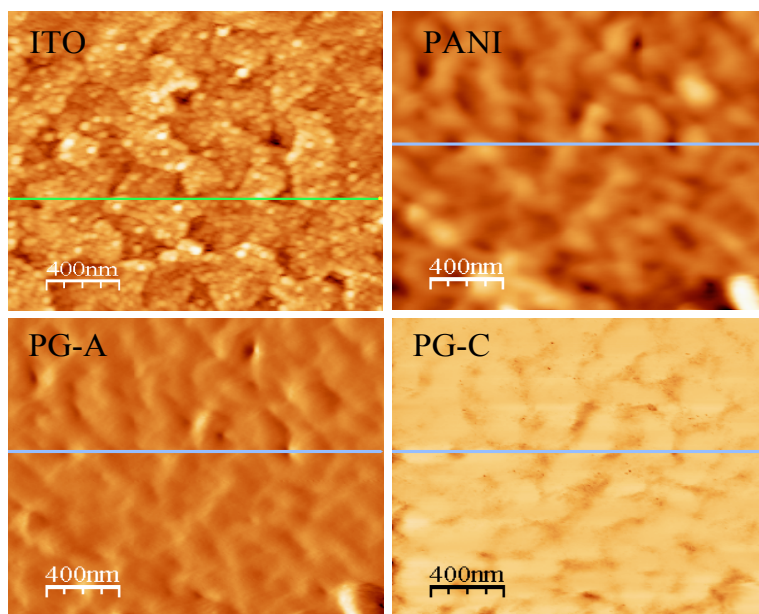


Fig. SI 5 Topographical AFM images of bare ITO, pure PANI film and PANI-GO films (sample PG-A and PG-C).

References:

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